

PCN#20160607002 Qualification of new Assembly & Test site (TI Taiwan) & New material set for the UCCx895DW Device family Change Notification / Sample Request

Date: 6/10/2016 To: TOKYO ELECTRON DEVICE (DSTR) PCN

Dear Customer:

This is an announcement of a change to a device that is currently offered by Texas Instruments. The details of this change are on the following pages.

We request you acknowledge receipt of this notification within **30** days of the date of this notice. Lack of acknowledgement of this notice within 30 days constitutes acceptance of the change. If you require samples or additional data to support your evaluation, please request within 30 days.

The changes discussed within this PCN will not take effect any earlier than **90** days from the date of this notification, unless customer agreement has been reached on an earlier implementation of the change. This notification period is per TI's standard process.

This notice does not change the end-of-life status of any product. Should product affected be on a previously issued product withdrawal/discontinuance notice, this notification does not extend the life of that product or change the life time buy offering/discontinuance plan.

For questions regarding this notice, contact your local Field Sales Representative or the PCN Manager (<u>PCN_ww_admin_team@list.ti.com</u>).

Sincerely,

PCN Team SC Business Services

20160607002 Attachment: 1

Products Affected:

The devices listed on this page are a subset of the complete list of affected devices. According to our records, these are the devices that you have purchased within the past twenty-four (24) months. The corresponding customer part number is also listed, if available.

DEVICE

CUSTOMER PART NUMBER

UCC3895DW UCC3895DWTR null null

Technical details of this Product Change follow on the next page(s).

PCN Number:			20160607002 PCN Date: 6/10/201						6/10/2016				
Title: Qualification of new Assembly & Test site (TI Taiwan) & New material set for the UCCx895DW Device family						for the							
Custom		PCN /			Dept	:	Quality Se	rvice	es				
Proposed 1 st Ship Da			:e:	9/	/10/2016	Est	Estimated Sample Availa		ability:	bility: Provided upon Request			
Change													
	embly Site	3	Assembly Pi			ocess		\boxtimes	Assembly Materials				
Desi				Electrical Sp						Mechanical Specification			ification
	Site	<u></u>	┥┝	╡┼	Packing/Sh				Test Process				
	er Bump S			Wafer Bump							er Bum		
	er Fab Sit	e		╡┼	Wafer Fab					wai	fer Fab F	roce	SS
					Part numb				L				
Descript	tion of C					PUN	De	tails					
	tion of Cl			d +/		the c		ification TI	Taire	van a	c an ada	lition	al Assembly &
								M differen					al Assellibly &
	V	Vhat					Ca	rsem		TI 1	「aiwan		
	Ν	1ount	Corr	про	und	S	ID#	434165		414	47858		
Mold		1old C	d Compound			S	ID#	438359	438359 421				
Bond		Bond V	nd Wire			A	۹u,	1.3 mils	(Cu, 0.96 mils			
	L	.eadfra	dframe				Sta	andard		Roughened			
Test coverage, insertions, conditions will remain consistent with current testing and verified with test MQ. Reason for Change: Continuity of Supply													
	<u> </u>	·	h Fit	. Fo	orm. Func	tion. (Oua	ality or Re	liab	ility (nositiv	e / 1	negative):
None					, , , , , , , , , , , , , , , , , , , ,		2					- / -	
Anticipa	ited impa	act or	n Ma	iter	ial Declar	ation							
Material Declaration			Material Declarations or Product Content reports are driven from production data and will be available following the production release. Upon production release the revised reports can be obtained from the <u>TI ECO website</u> .										
Changes	s to prod	uct ic	lent	ific	ation resu	ulting	fro	om this PC	N:				
Assen	nbly Site	Ass	Assembly Site Origin (22L)		2L) As	Assembly Country Code (21		e (21L	.) Assembly C		embly City		
Ca	rsem		CAR			MYS		Ipoh		Ipoh			
ТІТ	aiwan		TAI			TWN		Chun	ig Ho	o, New Taipei City			
Sample p	product sh	nipping	g lab	bel	(not actua	al prod	luct	label)			•		

MSL 2 /260C/1 YEAR SEAL DT MSL 1 /235C/UNLIM 03/29/04 (31T)LOT: 3959047/ML MSL 1 /235C/UNLIM 03/29/04 MSL 2 /260C/1 YEAR SEAL DT (4W) TKY (1T) 7523483 OPT: 39 (1)TO:1750 (2P) REV: (V) 0033 ITEM: 39 (2D) CSO: SHE (21L) CCO:	523483SI2) 0033317 1L) CC0:USA	
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Topside Device marking (if included): Assembly site code for CAR= V Assembly site code for TAI = T

Product Affected

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UCC2895DW	UCC2895DWTR	UCC3895DW	UCC3895DWTR	
UCC2895DWG4	UCC2895DWTRG4	UCC3895DWG4	UCC3895DWTRG4	



TI Information Selective Disclosure

Qualification Report UCC3895DWTR Assembly and Test Offload to TITL with Copper Wire

Product Attributes

Attributes	Qual Device: UCC3895DWTR	QBS Package Reference: ADS820U_QMI505MT_CU _SSTN	QBS Package Reference: ADS8504IBDW_QMI505 MT_CU_STD	QBS Package Reference: TPS2101D	QBS Package Reference: TSS721AD	QBS Package Reference: ULQ2003AQDRQ1_STDLF
Assembly Site	TAI	TAI	TAI	TAI	TAI	FMX
Package Family	SOIC WIDE	SOIC	SOIC	SOIC	SOIC	SOIC
Flammability Rating	-	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0
Wafer Fab Supplier	SFAB	TSMC WF2	DMOS5	DFAB	SFAB	SFAB
Wafer Fab Process	IMP-PWR2	0.60UM-TSMC	50HPA07	LBC3S	JI1	JI1-SLM

- QBS: Qual By Similarity

- Qual Device UCC3895DWTR is qualified at LEVEL2-260C

Qualification Results Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: UCC3895DWTR	QBS Package Reference: ADS820U_QMI505MT _CU_SSTN	QBS Package Reference: ADS8504IBDW_QMI505 MT_CU_STD	QBS Package Reference: TPS2101D	QBS Package Reference: TSS721AD	QBS Package Reference: ULQ2003AQDRQ1_ST DLF
AC	Autoclave 121C	96 Hours	-	-	1/77/0	-	-	3/231/0
HAST	Biased HAST, 130C/85%R H	96 Hours	-	-	-	-	-	3/231/0
HTOL	Life Test, 150C	408 Hours	-	-	-	-	-	3/231/0
HTSL	High Temp Storage Bake 150C	1000 Hours	-	-	-	-	-	1/45/0
HTSL	High Temp Storage Bake 170C	420 Hours	-	-	1/77/0	-	-	-
тс	Temperature Cycle, - 65/150C	500 Cycles	-	3/231/0	1/77/0	3/231/0	3/231/0	3/231/0
WBP	Bond Pull	Wires	Pass	-	-	-	-	-
WBS	Ball Bond Shear	Wires	Pass	-	-	-	-	-
- The foll - The foll - The foll Quality as Green/Pt	owing are equival owing are equival owing are equival	ent HTOL options ent HTSL options ent Temp Cycle o data is available	based on an activation based on an activation	energy of 0.7eV : 125C/1k H energy of 0.7eV : 150C/1k H C/125C/700 Cycles and -65	re Cycle, Thermal Shock, and lours, 140C/480 Hours, 150C/ lours, and 170C/420 Hours C/150C/500 Cycles		Hours	

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com